# No Free Lunch in Soft Error Protection?

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### **Results That Made Us Think**

[Seshia, Li, Mitra, DATE 2007]: validity of set of properties covering the specs of a communication chip

 Results: for two-thirds of flip-flops, properties hold even if a soft error occurs in that flip-flop (formally proven)
 Why?

### **Possible Explanations (1)**

#### Explanation 1: these flip-flops are redundant

- permanent errors on that flip-flops have no impact on system behavior (are masked)
- we don't know for sure, but typically two-thirds of the design are not redundant!

Explanation 2: they are one-cycle redundant

- one-cycle bit flips on that flip-flops are masked
- data for ISCAS circuits suggest that redundancy and one-cycle redundancy are very similar
  - see paper

### **Possible Explanations (3)**

- Explanation 3: these flip-flops are not redundant in classical sense
- But design resilient against soft errors on that flip-flops with respect to property set
- General concept valid for several applications
  - applications with a human user (multimedia)
  - errors handled by application (communication)
  - inherently error-tolerant applications (recognition, mining, synthesis, tracking, control)

### **Example: Cognitive Resilience**



- Are there errors which do not result in visible effects?
- Such errors require no hardening
   Details: our DSN paper
- Details: our DSN paper

## Summary

Difference between "redundant" and "resilient" appears to be large

derived by exclusion

Better understanding of "resilient" could lead to low-cost hardening of unreliable hardware (e.g. nano blocks)
Yes, this could be the free lunch!

#### Results

#### Metric for imaging applications

- composition of PSNR, SSIM, psychovisual model

#### Experiment: JPEG Compressor

- from www.opencores.org
- 54.8% error sites need no hardening



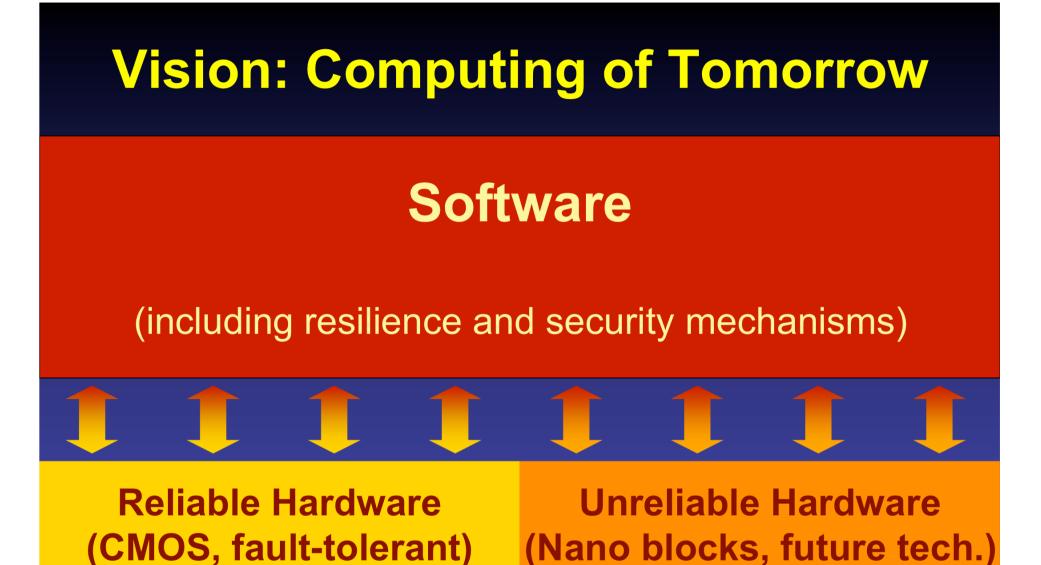




no error

acceptable error

unacceptable error



low integration density high energy consumption high integration density low energy consumption